

CD4001BC/CD4011BC

Quad 2-Input NOR Buffered B Series Gate • Quad 2-Input NAND Buffered B Series Gate

General Description

The CD4001BC and CD4011BC quad gates are monolithic complementary MOS (CMOS) integrated circuits constructed with N- and P-channel enhancement mode transistors. They have equal source and sink current capabilities and conform to standard B series output drive. The devices also have buffered outputs which improve transfer characteristics by providing very high gain.

All inputs are protected against static discharge with diodes to V_{DD} and V_{SS} .

Features

- Low power TTL:
Fan out of 2 driving 74L compatibility: or 1 driving 74LS
- 5V–10V–15V parametric ratings
- Symmetrical output characteristics
- Maximum input leakage 1 μ A at 15V over full temperature range

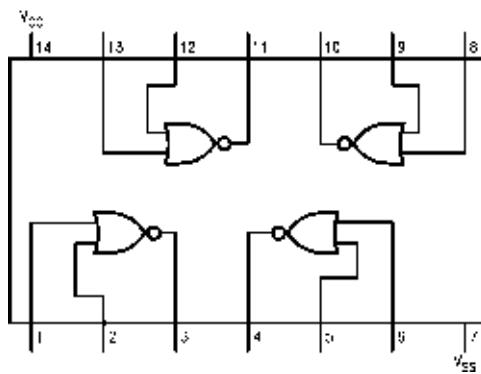
Ordering Code:

| Order Number | Package Number | Package Description |
|--------------|----------------|--|
| CD4001BCM | M14A | 14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150" Narrow |
| CD4001BCSJ | M14D | 14-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide |
| CD4001BCN | N14A | 14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide |
| CD4011BCM | M14A | 14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150" Narrow |
| CD4011BCN | N14A | 14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide |

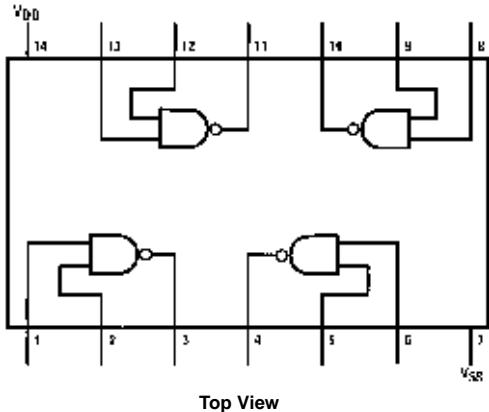
Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Connection Diagrams

Pin Assignments for DIP, SOIC and SOP
CD4001BC

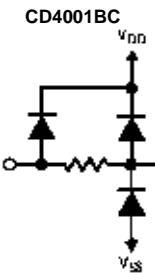
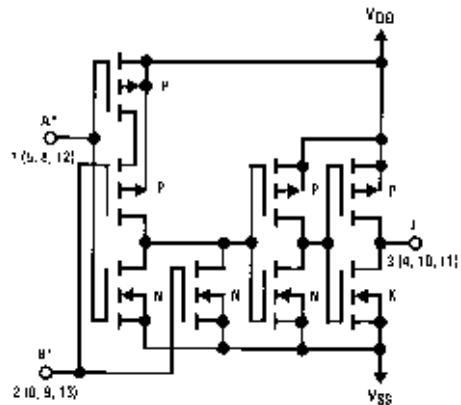


Pin Assignments for DIP and SOIC
CD4011BC

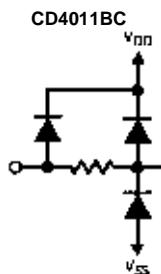
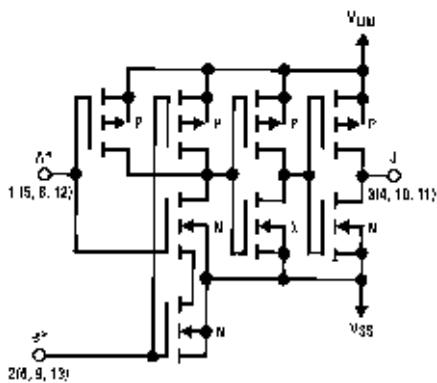


CD4001BC/CD4011BC

Schematic Diagrams



$\frac{1}{4}$ of device shown
 $J = \overline{A} + \overline{B}$
Logical "1" = HIGH
Logical "0" = LOW
All inputs protected by standard
CMOS protection circuit.



$\frac{1}{4}$ of device shown
 $J = \overline{A} + \overline{B}$
Logical "1" = HIGH
Logical "0" = LOW
All inputs protected by standard
CMOS protection circuit.

Absolute Maximum Ratings(Note 1)

(Note 2)

| | |
|-------------------------------|-------------------------------|
| Voltage at any Pin | -0.5V to V_{DD} +0.5V |
| Power Dissipation (P_D) | |
| Dual-In-Line | 700 mW |
| Small Outline | 500 mW |
| V_{DD} Range | -0.5 V_{DC} to +18 V_{DC} |
| Storage Temperature (T_S) | -65°C to +150°C |
| Lead Temperature (T_L) | |
| (Soldering, 10 seconds) | 260°C |

Recommended Operating ConditionsOperating Range (V_{DD}) 3 V_{DC} to 15 V_{DC}

Operating Temperature Range

CD4001BC, CD4011BC -40°C to +85°C

Note 1: "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. Except for "Operating Temperature Range" they are not meant to imply that the devices should be operated at these limits. The Electrical Characteristics tables provide conditions for actual device operation.

Note 2: All voltages measured with respect to V_{SS} unless otherwise specified.

DC Electrical Characteristics (Note 2)

| Symbol | Parameter | Conditions | -40°C | | +25°C | | | +85°C | | Units |
|----------|---------------------------------------|---|-------|-------|-------|------------|-------|-------|------|-------|
| | | | Min | Max | Min | Typ | Max | Min | Max | |
| I_{DD} | Quiescent Device Current | $V_{DD} = 5V, V_{IN} = V_{DD}$ or V_{SS} | | 1 | | 0.004 | 1 | | 7.5 | µA |
| | | $V_{DD} = 10V, V_{IN} = V_{DD}$ or V_{SS} | | 2 | | 0.005 | 2 | | 15 | µA |
| | | $V_{DD} = 15V, V_{IN} = V_{DD}$ or V_{SS} | | 4 | | 0.006 | 4 | | 30 | µA |
| V_{OL} | LOW Level Output Voltage | $V_{DD} = 5V$ | | 0.05 | | 0 | 0.05 | | 0.05 | V |
| | | $V_{DD} = 10V \quad I_{O1} < 1 \mu A$ | | 0.05 | | 0 | 0.05 | | 0.05 | V |
| | | $V_{DD} = 15V$ | | 0.05 | | 0 | 0.05 | | 0.05 | V |
| V_{OH} | HIGH Level Output Voltage | $V_{DD} = 5V$ | 4.95 | | 4.95 | 5 | | 4.95 | | V |
| | | $V_{DD} = 10V \quad I_{O1} < 1 \mu A$ | 9.95 | | 9.95 | 10 | | 9.95 | | V |
| | | $V_{DD} = 15V$ | 14.95 | | 14.95 | 15 | | 14.95 | | V |
| V_{IL} | LOW Level Input Voltage | $V_{DD} = 5V, V_O = 4.5V$ | | 1.5 | | 2 | 1.5 | | 1.5 | V |
| | | $V_{DD} = 10V, V_O = 9.0V$ | | 3.0 | | 4 | 3.0 | | 3.0 | V |
| | | $V_{DD} = 15V, V_O = 13.5V$ | | 4.0 | | 6 | 4.0 | | 4.0 | V |
| V_{IH} | HIGH Level Input Voltage | $V_{DD} = 5V, V_O = 0.5V$ | 3.5 | | 3.5 | 3 | | 3.5 | | V |
| | | $V_{DD} = 10V, V_O = 1.0V$ | 7.0 | | 7.0 | 6 | | 7.0 | | V |
| | | $V_{DD} = 15V, V_O = 1.5V$ | 11.0 | | 11.0 | 9 | | 11.0 | | V |
| I_{OL} | LOW Level Output Current (Note 3) | $V_{DD} = 5V, V_O = 0.4V$ | 0.52 | | 0.44 | 0.88 | | 0.36 | | mA |
| | | $V_{DD} = 10V, V_O = 0.5V$ | 1.3 | | 1.1 | 2.25 | | 0.9 | | mA |
| | | $V_{DD} = 15V, V_O = 1.5V$ | 3.6 | | 3.0 | 8.8 | | 2.4 | | mA |
| I_{OH} | HIGH Level Output Current (Note 3) | $V_{DD} = 5V, V_O = 4.6V$ | -0.52 | | -0.44 | -0.88 | | -0.36 | | mA |
| | | $V_{DD} = 10V, V_O = 9.5V$ | -1.3 | | -1.1 | -2.25 | | -0.9 | | mA |
| | | $V_{DD} = 15V, V_O = 13.5V$ | -3.6 | | -3.0 | -8.8 | | -2.4 | | mA |
| I_{IN} | Input Current | $V_{DD} = 15V, V_{IN} = 0V$ | | -0.30 | | -10^{-5} | -0.30 | | -1.0 | µA |
| | | $V_{DD} = 15V, V_{IN} = 15V$ | | 0.30 | | 10^{-5} | 0.30 | | 1.0 | µA |

Note 3: I_{OL} and I_{OH} are tested one output at a time.**AC Electrical Characteristics** (Note 4)CD4001BC: $T_A = 25^\circ C$, Input t_f ; $t_f = 20 \text{ ns}$. $C_L = 50 \text{ pF}$, $R_L = 200\text{k}$. Typical temperature coefficient is 0.3%/°C.

| Symbol | Parameter | Conditions | Typ | Max | Units |
|--------------------|--|----------------|-----|-----|-------|
| t_{PHL} | Propagation Delay Time, HIGH-to-LOW Level | $V_{DD} = 5V$ | 120 | 250 | ns |
| | | $V_{DD} = 10V$ | 50 | 100 | ns |
| | | $V_{DD} = 15V$ | 35 | 70 | ns |
| t_{PLH} | Propagation Delay Time, LOW-to-HIGH Level | $V_{DD} = 5V$ | 110 | 250 | ns |
| | | $V_{DD} = 10V$ | 50 | 100 | ns |
| | | $V_{DD} = 15V$ | 35 | 70 | ns |
| t_{THL}, t_{TLH} | Transition Time | $V_{DD} = 5V$ | 90 | 200 | ns |
| | | $V_{DD} = 10V$ | 50 | 100 | ns |
| | | $V_{DD} = 15V$ | 40 | 80 | ns |
| C_{IN} | Average Input Capacitance | Any Input | 5 | 7.5 | pF |
| C_{PD} | Power Dissipation Capacity | Any Gate | 14 | | pF |

Note 4: AC Parameters are guaranteed by DC correlated testing.

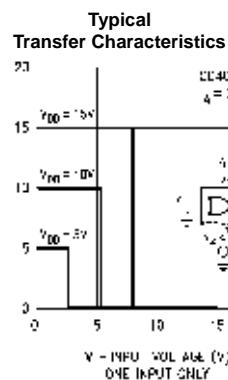
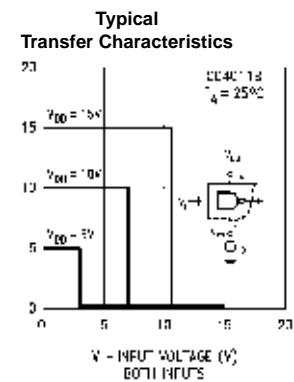
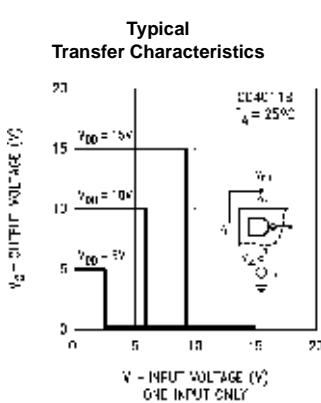
AC Electrical Characteristics (Note 5)

CD4011BC: $T_A = 25^\circ\text{C}$, Input t_i ; $t_f = 20 \text{ ns}$. $C_L = 50 \text{ pF}$, $R_L = 200\text{k}$. Typical Temperature Coefficient is $0.3\%/\text{C}$.

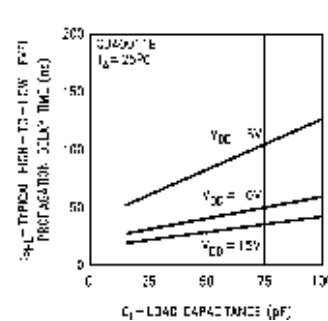
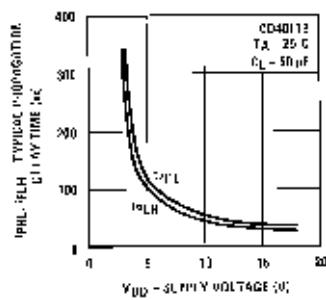
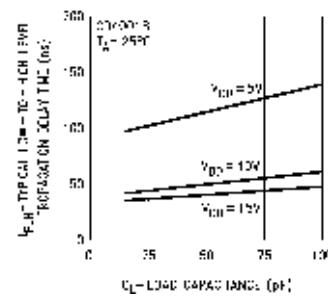
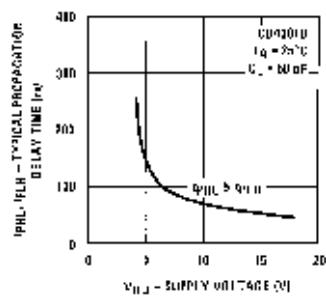
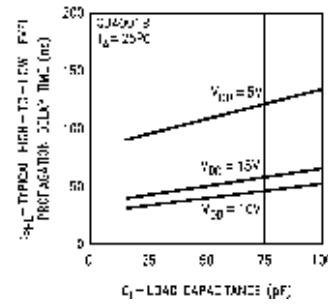
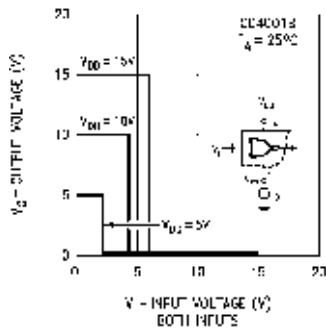
| Symbol | Parameter | Conditions | Typ | Max | Units |
|--------------------|---|-----------------------|-----|-----|-------|
| t_{PHL} | Propagation Delay, HIGH-to-LOW Level | $V_{DD} = 5\text{V}$ | 120 | 250 | ns |
| | | $V_{DD} = 10\text{V}$ | 50 | 100 | ns |
| | | $V_{DD} = 15\text{V}$ | 35 | 70 | ns |
| t_{PLH} | Propagation Delay, LOW-to-HIGH Level | $V_{DD} = 5\text{V}$ | 85 | 250 | ns |
| | | $V_{DD} = 10\text{V}$ | 40 | 100 | ns |
| | | $V_{DD} = 15\text{V}$ | 30 | 70 | ns |
| t_{THL}, t_{TLH} | Transition Time | $V_{DD} = 5\text{V}$ | 90 | 200 | ns |
| | | $V_{DD} = 10\text{V}$ | 50 | 100 | ns |
| | | $V_{DD} = 15\text{V}$ | 40 | 80 | ns |
| C_{IN} | Average Input Capacitance | Any Input | 5 | 7.5 | pF |
| C_{PD} | Power Dissipation Capacity | Any Gate | 14 | | pF |

Note 5: AC Parameters are guaranteed by DC correlated testing.

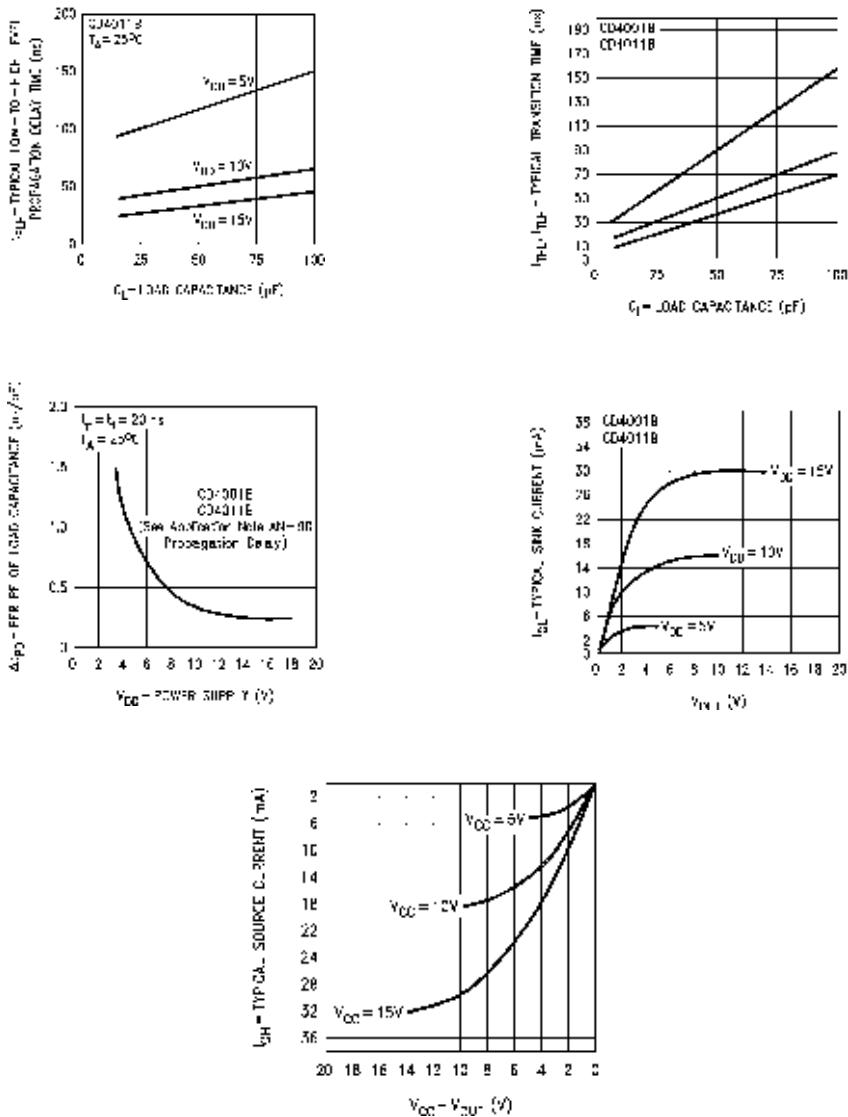
Typical Performance Characteristics



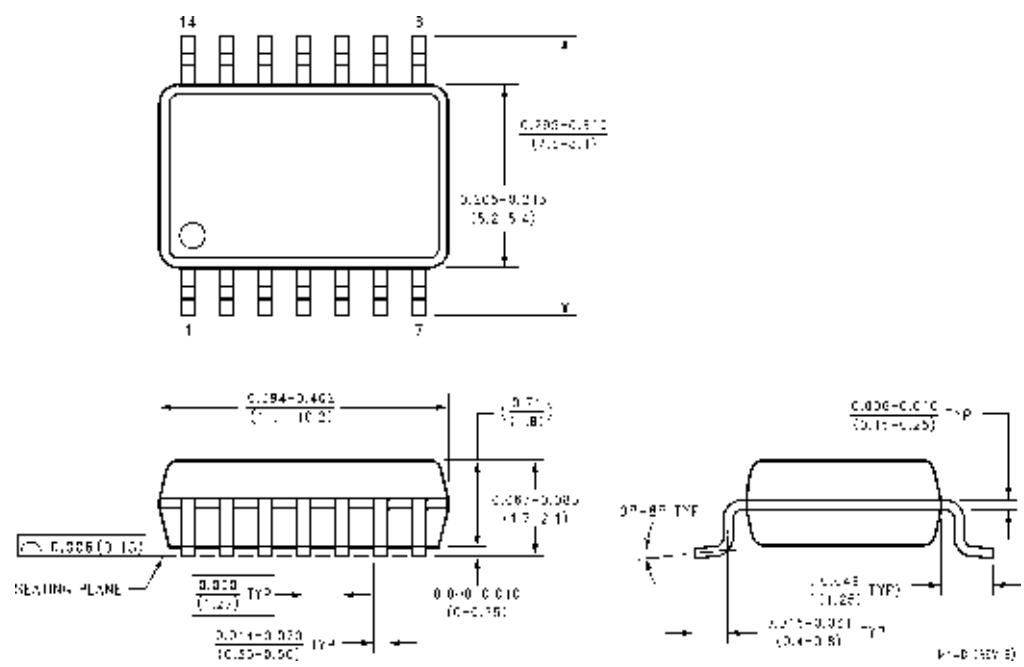
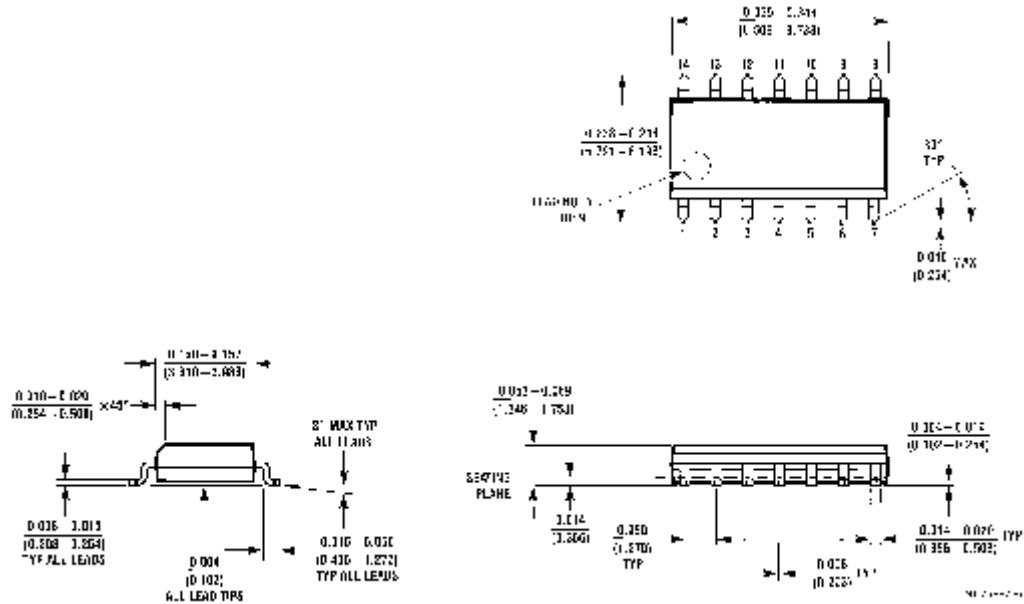
Typical Transfer Characteristics



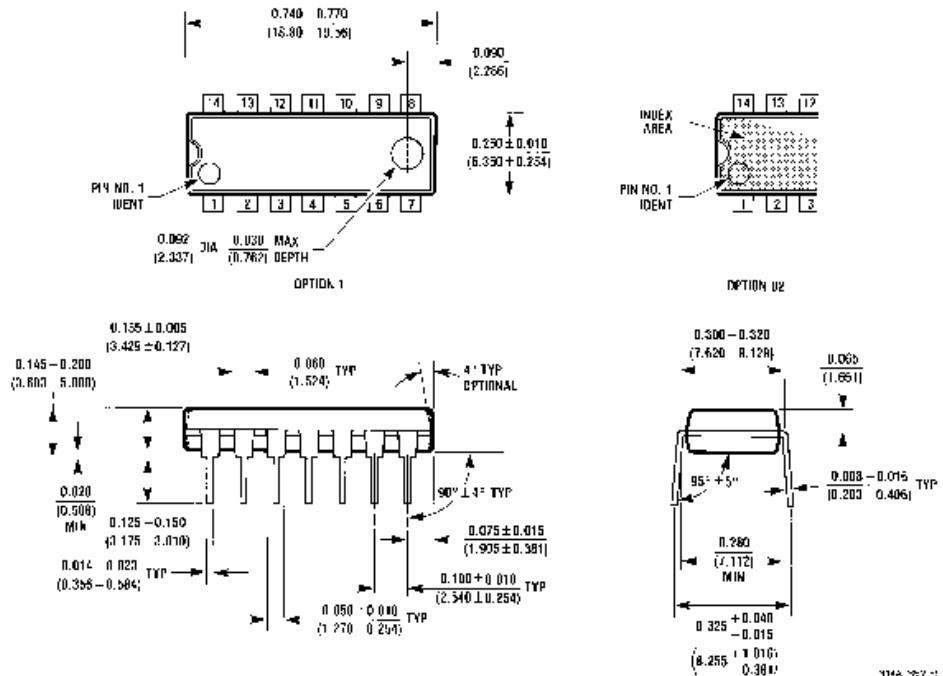
CD4001BC/CD4011BC



Physical Dimensions inches (millimeters) unless otherwise noted



Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



**14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide
Package Number N14A**

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